	Application/Control No.	Applicant(s)/Patent under Reexamination
Search Notes	10/795,771	SHAN ET AL.
	Examiner	Art Unit
	Timothy C. Vanoy	1754

SEARCHED			
Class	Subclass	Date	Examiner
423	625	8/22/2006	_(sig)_
423	628	8/22/2006	_(sig)_
423	593.1	8/22/2006	_(sig)_
423	594.1	8/22/2006	_(sig)_
423	594.3	8/22/2006	_(sig)_
423	594.5	8/22/2006	_(sig)_
423	595	8/22/2006	_(sig)_
423	598	8/22/2006	_(sig)_
423	599	8/22/2006	_(sig)_
423	600	8/22/2006	_(sig)_
423	594.8	8/22/2006	_(sig)_
423	594.9	8/22/2006	_(sig)_
423	594.13	8/22/2006	_(sig)_
423	594.14	8/22/2006	_(sig)_

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor name search conducted.	8/22/2006	_(sig)_

Search Notes (continued)	Application/Control No.	Applicant(s)/Patent under Reexamination
‖‖‖‖‖‖‖‖‖‖‖	10/795,771	SHAN ET AL.
	Examiner	Art Unit
	Timothy C. Vanoy	1754

SEARCHED			
Class	Subclass	Date	Examiner
423	263	8/22/2006	*(initials)*
423	111	8/22/2006	*(initials)*
423	115	8/22/2006	*(initials)*
423	122	8/22/2006	*(initials)*

SEARCH NOTES (INCLUDING SEARCH STRATEGY)	DATE	EXMR

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner